



FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. B-987	SERIAL NO. 09/869,274		
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT A. NISHIMURA et al			
				FILING DATE June 26, 2001	GROUP		
U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)	
AA	6,030,890	2/29/00	Iwabuchi				
AB	6,008,543	12/28/99	Iwabuchi				
AC	5,554,940	9/10/96	Hubacher				
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
FOREIGN PATENT DOCUMENTS							
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL	4-26537	3/3/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
AM	4-96343	3/27/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
AN	5-218042	8/27/93	Japan			<input type="checkbox"/>	<input type="checkbox"/>
AO	8-250498	9/27/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
AP	8-64633	3/8/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
AR	IEEE/CPMT INTL ELECTRONICS MANUFACTURING TECHNOLOGY SYMPOSIUM, "Impact of Wafer Probe Damage on Flip Chip Yields and Reliability", M. Varnau et al, pp. 293-297.						
AS							
AT							
EXAMINER				DATE CONSIDERED			

RECEIVED
 JAN 13 2004
 TECHNOLOGY CENTER 2800



FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. B-987		SERIAL NO. 09/869,274	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT A. NISHIMURA et al			
				FILING DATE June 26, 2001		GROUP	
U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (if Appropriate)	
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	AL 8-340029	12/24/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM 8-29451	2/2/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	AR						
	AS						
	AT						
EXAMINER				DATE CONSIDERED			

RECEIVED
JAN 3 2004
TECHNOLOGY CENTER 22000